

<b>Notice of References Cited</b>	Application/Control No. 10/663,714	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,103,543	08-2000	Uemura et al.	438/46
	B	US-			
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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